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Application/Control No.	Applicant(s)/Patent under Reexamination
10/540,317	YULE ET AL.
Examiner	Art Unit
Dao L. Phan	3662

	SEAR	CHED	
Class	Subclass	Date	Examiner
342	357.01	3/31/2006	DP
	357.06		
	357.12		
701	207		_
	213		
	215		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East text searched (See a Hached)	3/31/2006	DP